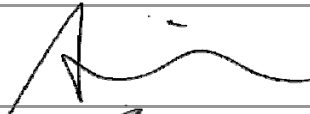




**Product/Process Change Notification**

PCN#	Effective Date	Issue Date
2014-08-01C-16	2015/2/1	2014/8/1
PCN Classification	Product Category	
Major	SOD-123 Package	
Subject		
Add a molding vendor		
Affected Product(s)		
As attachment		
Description of Change(s)		
In order to avoid shortage of the material, and enhance the speed of delivery, thus, we add a new vendor.		
Content of Change(s)		
Add Molding vendor--ELER-8-100HFE		
Impact(s)		
N/A		
Attachment(s)		
Reliability Teat Report.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website <http://www.secosgmbh.com>

Affected Products

SCS0520P	BAT54P
SCS0530P	BAT42W
SCS0540P	BAT43W
SCS0560P	SD103BW
SCS05100P	SD101CW
SCS120P	SD103AW
SCS130P	SD101BW
SCS140P	SD101AW
SCS160P	BAT46W
SCS1100P	1N4148W
SCS220P	BAV16P
SCS230P	1N4448W
SCS240P	BAS116W
SCS0520LP	MMSD914
SCS0530LP	BAV19P
SCS0540LP	BAV20P
SCK140LP	BAV21P
SCK120LP	MMSZ46xx Series
SCK220LP	BZT52C Series
SD103CW	MMSZ52xxB Series



## Reliability Testing Summary Report

Date: 2014/06/30

Document No.: SH14 -06- 31

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SCS1100P	100 ± 5°C, 100% VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SCS1100P	150°C, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SCS1100P	121°C, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SCS1100P	-55°C/30min, 150°C/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SCS1100P	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SCS1100P	85 ± 2°C, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	SCS1100P	245 ± 5°C, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

**Judgment:**

qualified     unqualified

Testing Start Date: 2014.05.05    Testing End Date: 2014.06.30

Tester: Leo Hsia    Approval: Peter Yang



## Electrical Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
1	798.7mV	111.3V	0.976uA
2	795.1mV	109.4V	0.965uA
3	796.6mV	111.8V	0.844uA
4	796.9mV	115.0V	0.951uA
5	793.8mV	115.6V	1.116uA
6	800.3mV	111.6V	1.152uA
7	798.7mV	115.1V	1.083uA
8	791.4mV	110.5V	0.923uA
9	799.4mV	115.0V	1.053uA
10	800.6mV	111.4V	0.974uA
11	793.5mV	110.8V	0.893uA
12	794.9mV	115.6V	1.002uA
13	799.9mV	115.1V	0.923uA
14	797.9mV	113.6V	1.041uA
15	797.1mV	109.6V	0.933uA
16	793.6mV	110.6V	1.061uA
17	793.2mV	115.5V	0.868uA
18	792.3mV	110.0V	1.132uA
19	797.6mV	113.5V	0.896uA
20	790.9mV	110.5V	1.033uA
21	792.4mV	112.9V	1.019uA
22	790.7mV	112.7V	1.140uA
23	799.2mV	115.6V	1.012uA
24	791.4mV	115.4V	1.125uA
25	793.1mV	109.7V	0.955uA
26	792.8mV	115.2V	0.935uA
27	791.6mV	115.2V	0.960uA
28	793.3mV	115.7V	0.978uA
29	790.9mV	111.5V	1.037uA
30	793.9mV	115.4V	1.130uA
31	798.5mV	111.3V	0.947uA



## Electrical Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
32	795.2mV	112.0V	0.845uA
33	793.4mV	113.6V	1.137uA
34	793.0mV	113.6V	1.108uA
35	801.3mV	112.1V	0.937uA
36	799.6mV	112.1V	1.078uA
37	790.5mV	110.8V	1.078uA
38	798.9mV	111.0V	0.984uA
39	793.3mV	109.6V	0.904uA
40	792.5mV	111.4V	1.097uA
41	798.5mV	113.1V	1.155uA
42	796.2mV	115.6V	1.109uA
43	800.7mV	114.9V	1.111uA
44	790.6mV	115.2V	1.058uA
45	800.4mV	109.8V	1.052uA
46	797.8mV	111.2V	0.873uA
47	800.2mV	113.5V	1.014uA
48	796.6mV	112.0V	0.945uA
49	796.1mV	110.5V	0.937uA
50	791.1mV	113.1V	0.956uA
51	792.8mV	114.5V	1.030uA
52	801.0mV	109.7V	1.002uA
53	798.2mV	109.9V	0.885uA
54	791.7mV	110.9V	1.015uA
55	798.2mV	112.7V	1.009uA
56	796.3mV	115.0V	0.928uA
57	801.4mV	114.9V	0.885uA
58	793.4mV	115.6V	0.961uA
59	801.0mV	113.9V	1.158uA
60	796.2mV	114.0V	0.885uA
61	797.4mV	115.4V	0.956uA
62	793.2mV	115.1V	1.148uA



## Electrical Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 25°C

Test Date: 2014.05.05 ~ 2014.05.05

Test Standard : Specifications

Operator: Leo Hsia

Test Result: PASS

No	VF (mV)	VB (V)	IR (uA)
63	799.2mV	114.9V	0.882uA
64	795.6mV	110.1V	1.145uA
65	793.7mV	110.2V	0.890uA
66	799.8mV	111.6V	0.945uA
67	793.3mV	113.4V	1.114uA
68	799.3mV	109.7V	0.918uA
69	793.3mV	111.5V	1.008uA
70	800.7mV	110.5V	1.084uA
71	799.9mV	110.5V	1.004uA
72	796.9mV	111.5V	1.161uA
73	796.2mV	111.6V	1.132uA
74	795.8mV	111.5V	1.016uA
75	796.5mV	113.7V	1.038uA
76	796.3mV	114.8V	1.094uA
77	799.4mV	110.5V	1.127uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temperature Reverse Bias Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	795.8mV	115.0V	1.136uA	792.8mV	110.0V	1.043uA
2	794.2mV	110.8V	0.904uA	800.0mV	113.8V	0.856uA
3	790.7mV	110.3V	1.084uA	790.7mV	115.4V	1.003uA
4	798.8mV	115.0V	1.132uA	794.3mV	113.6V	0.968uA
5	799.6mV	114.7V	1.132uA	794.3mV	112.0V	0.933uA
6	791.6mV	109.5V	0.844uA	801.5mV	114.5V	0.912uA
7	797.9mV	114.8V	0.918uA	795.6mV	112.0V	1.121uA
8	794.7mV	114.7V	1.109uA	798.4mV	111.6V	1.163uA
9	799.3mV	115.5V	1.126uA	797.6mV	113.8V	0.939uA
10	792.4mV	112.6V	0.879uA	795.5mV	114.0V	1.005uA
11	797.3mV	111.9V	1.044uA	800.5mV	115.2V	1.151uA
12	797.0mV	112.0V	0.878uA	799.1mV	110.8V	1.145uA
13	794.1mV	110.1V	0.913uA	796.5mV	109.8V	0.957uA
14	791.2mV	112.6V	1.116uA	799.3mV	114.2V	1.109uA
15	797.5mV	109.9V	0.951uA	801.5mV	111.0V	1.167uA
16	792.7mV	114.3V	0.944uA	798.8mV	113.0V	1.085uA
17	796.0mV	112.1V	1.124uA	790.6mV	114.2V	0.830uA
18	797.1mV	114.9V	0.918uA	791.4mV	115.4V	1.097uA
19	799.2mV	113.5V	1.148uA	800.3mV	115.2V	0.864uA
20	791.4mV	111.7V	0.876uA	799.3mV	110.7V	0.901uA
21	795.0mV	113.4V	1.012uA	796.5mV	114.6V	0.999uA
22	792.7mV	113.4V	1.134uA	792.8mV	111.2V	0.899uA
23	796.8mV	113.4V	0.842uA	798.5mV	114.7V	0.863uA
24	798.5mV	109.6V	0.857uA	795.2mV	111.2V	0.855uA
25	794.8mV	115.1V	1.142uA	792.5mV	115.0V	0.969uA
26	792.0mV	114.6V	0.901uA	793.4mV	109.6V	0.888uA
27	800.7mV	113.0V	0.973uA	799.2mV	115.5V	1.114uA
28	798.2mV	113.5V	0.903uA	798.4mV	110.1V	0.878uA
29	799.3mV	113.9V	0.903uA	796.3mV	110.0V	1.106uA
30	799.1mV	113.0V	1.126uA	794.2mV	110.8V	0.922uA



## High Temperature Reverse Bias Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	793.7mV	109.4V	1.155uA	793.6mV	114.0V	0.973uA
32	798.1mV	115.4V	1.112uA	800.1mV	113.8V	1.110uA
33	792.1mV	112.1V	0.899uA	795.4mV	115.3V	1.132uA
34	796.6mV	115.6V	1.168uA	792.1mV	109.9V	1.129uA
35	794.4mV	109.7V	1.155uA	800.1mV	109.7V	0.968uA
36	795.7mV	110.3V	1.118uA	797.2mV	114.3V	0.943uA
37	800.2mV	112.2V	1.106uA	799.0mV	109.8V	1.050uA
38	801.3mV	110.3V	0.965uA	799.3mV	115.5V	0.983uA
39	790.7mV	115.5V	0.945uA	794.1mV	114.1V	0.922uA
40	792.6mV	112.1V	0.862uA	793.8mV	113.3V	0.952uA
41	793.2mV	115.7V	1.045uA	793.2mV	109.9V	0.945uA
42	798.5mV	109.5V	1.110uA	794.0mV	114.0V	0.987uA
43	800.7mV	113.0V	1.155uA	797.2mV	112.9V	0.911uA
44	797.1mV	111.5V	1.144uA	792.8mV	114.8V	1.069uA
45	794.3mV	115.4V	1.097uA	792.0mV	113.1V	0.845uA
46	792.9mV	110.5V	0.862uA	800.9mV	115.4V	0.883uA
47	792.9mV	114.2V	0.916uA	794.2mV	112.1V	1.161uA
48	793.8mV	109.8V	0.826uA	798.0mV	115.5V	0.883uA
49	798.0mV	115.3V	1.088uA	794.8mV	114.3V	0.902uA
50	790.7mV	112.7V	0.858uA	798.7mV	110.7V	0.943uA
51	794.2mV	112.4V	0.921uA	791.1mV	114.6V	0.937uA
52	791.9mV	110.5V	1.043uA	797.1mV	113.5V	0.873uA
53	799.9mV	110.7V	0.866uA	797.7mV	114.2V	0.902uA
54	793.5mV	110.2V	0.839uA	793.2mV	111.3V	0.853uA
55	801.1mV	114.7V	0.937uA	800.7mV	109.6V	1.145uA
56	800.9mV	112.0V	1.046uA	793.4mV	112.9V	1.088uA
57	793.2mV	115.3V	0.906uA	800.7mV	113.8V	1.004uA
58	792.5mV	113.9V	0.867uA	798.5mV	110.6V	0.970uA
59	795.5mV	112.0V	0.895uA	797.4mV	111.0V	1.009uA
60	797.6mV	112.8V	1.160uA	796.3mV	115.3V	1.134uA





## High Temperature Reverse Bias Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 100 ± 5°C, 100% VR, T = 1000 hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	793.3mV	111.8V	1.086uA	801.1mV	114.6V	0.848uA
62	799.9mV	110.2V	0.927uA	798.0mV	109.6V	0.839uA
63	797.0mV	111.9V	1.099uA	800.8mV	111.4V	1.149uA
64	798.3mV	109.8V	1.025uA	792.5mV	113.8V	1.121uA
65	801.1mV	114.3V	0.834uA	795.4mV	114.0V	0.987uA
66	795.6mV	110.1V	0.980uA	799.5mV	112.7V	1.133uA
67	793.8mV	113.9V	1.100uA	798.0mV	112.5V	0.953uA
68	791.2mV	113.7V	0.904uA	793.8mV	111.3V	0.855uA
69	790.6mV	114.0V	0.897uA	796.3mV	111.5V	1.169uA
70	800.6mV	111.5V	0.964uA	791.0mV	115.1V	0.968uA
71	799.1mV	113.9V	0.827uA	790.8mV	112.8V	1.135uA
72	801.4mV	111.6V	1.013uA	797.0mV	112.2V	0.933uA
73	801.4mV	114.4V	0.834uA	798.4mV	111.0V	1.018uA
74	796.6mV	113.5V	1.081uA	797.0mV	112.1V	1.016uA
75	794.1mV	112.9V	1.039uA	790.7mV	114.7V	1.085uA
76	797.9mV	112.1V	0.979uA	791.9mV	113.1V	1.139uA
77	799.4mV	112.4V	0.828uA	798.2mV	111.3V	0.927uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temperature Storage Life Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	794.9mV	114.0V	0.933uA	790.7mV	114.2V	0.904uA
2	797.9mV	110.5V	1.031uA	797.0mV	109.7V	0.899uA
3	792.5mV	114.3V	0.944uA	791.5mV	114.3V	1.077uA
4	793.0mV	115.4V	1.020uA	793.7mV	113.0V	1.112uA
5	792.3mV	111.5V	1.117uA	796.8mV	112.9V	0.936uA
6	790.9mV	111.2V	1.156uA	801.1mV	113.9V	0.970uA
7	793.3mV	115.2V	0.865uA	800.6mV	110.2V	0.848uA
8	790.8mV	111.0V	1.115uA	792.1mV	111.7V	1.144uA
9	797.5mV	112.2V	0.854uA	791.5mV	115.6V	1.012uA
10	801.3mV	112.3V	0.894uA	797.4mV	111.5V	0.938uA
11	794.6mV	110.2V	1.094uA	792.3mV	111.4V	1.035uA
12	798.1mV	115.0V	0.971uA	792.0mV	109.6V	1.122uA
13	790.5mV	114.6V	1.109uA	795.8mV	113.9V	0.984uA
14	800.6mV	112.8V	1.002uA	796.8mV	112.5V	1.059uA
15	791.8mV	111.7V	0.928uA	794.0mV	110.2V	0.962uA
16	797.5mV	113.7V	0.903uA	800.1mV	114.0V	0.996uA
17	795.3mV	110.1V	1.140uA	795.6mV	114.4V	0.895uA
18	792.6mV	114.2V	0.890uA	793.3mV	113.3V	1.135uA
19	793.7mV	112.8V	1.040uA	799.1mV	115.3V	1.063uA
20	800.0mV	111.6V	1.020uA	793.2mV	115.4V	0.927uA
21	791.6mV	114.9V	1.103uA	801.3mV	112.6V	1.039uA
22	796.1mV	114.0V	0.957uA	799.0mV	112.7V	0.886uA
23	792.7mV	110.9V	1.035uA	798.7mV	114.2V	1.027uA
24	798.3mV	114.7V	0.943uA	790.9mV	112.8V	0.990uA
25	795.8mV	113.2V	1.028uA	793.6mV	110.3V	0.881uA
26	793.4mV	114.7V	0.885uA	794.4mV	115.1V	1.084uA
27	793.6mV	112.8V	1.038uA	790.7mV	115.7V	0.973uA
28	798.0mV	114.8V	0.854uA	790.6mV	115.0V	1.138uA
29	799.9mV	113.4V	0.910uA	790.8mV	112.0V	0.933uA
30	793.5mV	111.8V	1.081uA	798.0mV	114.6V	1.108uA



## High Temperature Storage Life Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	800.9mV	113.2V	1.020uA	800.9mV	112.6V	1.103uA
32	800.0mV	111.5V	1.118uA	798.7mV	112.2V	1.008uA
33	797.1mV	109.8V	0.968uA	798.6mV	112.4V	1.140uA
34	791.1mV	110.7V	0.944uA	799.3mV	111.6V	0.885uA
35	794.2mV	113.6V	0.886uA	792.6mV	115.3V	1.159uA
36	797.4mV	113.2V	0.867uA	791.2mV	110.0V	0.844uA
37	792.0mV	114.9V	0.870uA	800.3mV	113.5V	0.855uA
38	791.7mV	113.6V	1.041uA	795.1mV	110.3V	0.855uA
39	796.8mV	111.5V	0.963uA	797.4mV	115.3V	0.929uA
40	800.7mV	114.6V	0.935uA	797.6mV	114.1V	0.862uA
41	792.4mV	113.8V	1.108uA	798.2mV	114.4V	1.036uA
42	796.0mV	111.3V	1.130uA	798.6mV	110.6V	1.118uA
43	794.4mV	114.4V	1.024uA	791.7mV	110.9V	0.855uA
44	792.7mV	115.6V	0.872uA	800.2mV	113.7V	0.853uA
45	793.1mV	113.0V	1.151uA	791.3mV	111.7V	1.012uA
46	794.9mV	114.1V	1.114uA	798.1mV	111.8V	0.921uA
47	797.2mV	111.8V	1.022uA	793.3mV	113.3V	0.999uA
48	801.0mV	110.2V	1.122uA	800.2mV	115.2V	1.026uA
49	799.7mV	109.7V	1.096uA	801.1mV	113.7V	1.150uA
50	790.4mV	110.4V	1.022uA	797.9mV	109.6V	1.010uA
51	794.5mV	112.1V	0.858uA	792.2mV	110.1V	1.035uA
52	796.0mV	109.7V	0.852uA	797.6mV	111.0V	1.142uA
53	791.8mV	113.3V	0.918uA	796.2mV	109.8V	1.160uA
54	800.8mV	111.2V	0.938uA	798.8mV	112.6V	1.059uA
55	797.5mV	111.3V	0.869uA	794.6mV	113.7V	1.038uA
56	797.7mV	109.8V	1.100uA	799.0mV	111.8V	0.873uA
57	797.5mV	115.4V	1.018uA	791.4mV	113.3V	1.141uA
58	790.4mV	114.0V	0.926uA	798.7mV	112.6V	1.055uA
59	795.0mV	113.4V	1.061uA	796.6mV	113.4V	1.132uA
60	797.3mV	111.3V	1.027uA	795.4mV	113.8V	0.946uA



## High Temperature Storage Life Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 150°C, 1000Hrs

Test Date: 2014.05.05 ~ 2014.06.15

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	797.9mV	109.5V	0.832uA	795.2mV	109.9V	0.974uA
62	792.9mV	110.6V	0.971uA	793.1mV	113.6V	0.872uA
63	790.5mV	115.3V	1.103uA	790.5mV	109.6V	0.834uA
64	797.5mV	111.2V	0.897uA	794.4mV	111.5V	0.995uA
65	799.2mV	113.2V	1.048uA	797.1mV	110.9V	1.046uA
66	799.9mV	110.1V	0.898uA	792.6mV	113.6V	0.883uA
67	800.3mV	110.2V	0.956uA	794.4mV	111.9V	0.891uA
68	795.8mV	115.5V	1.062uA	794.2mV	115.3V	1.015uA
69	800.5mV	114.1V	1.002uA	799.8mV	115.5V	1.138uA
70	795.0mV	115.5V	1.018uA	792.5mV	113.6V	0.832uA
71	796.6mV	114.4V	1.118uA	799.0mV	113.2V	1.005uA
72	796.8mV	109.8V	1.072uA	790.5mV	111.4V	0.881uA
73	801.3mV	114.5V	0.845uA	791.5mV	113.3V	1.052uA
74	792.7mV	112.0V	1.083uA	797.5mV	113.3V	1.091uA
75	800.4mV	112.5V	0.943uA	799.2mV	113.6V	0.999uA
76	792.5mV	112.1V	0.878uA	797.5mV	114.7V	1.047uA
77	794.0mV	115.3V	1.121uA	798.8mV	111.8V	1.158uA

Made By: Leo Hsia

Approval: Peter Yang



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	793.6mV	109.5V	0.970uA	799.5mV	109.8V	0.975uA
2	798.7mV	114.2V	0.836uA	799.9mV	114.5V	1.134uA
3	798.7mV	114.0V	1.132uA	798.7mV	111.8V	1.013uA
4	800.0mV	114.0V	0.906uA	800.3mV	113.6V	0.926uA
5	801.0mV	114.1V	0.896uA	791.9mV	111.6V	1.073uA
6	794.8mV	109.5V	1.146uA	793.7mV	113.7V	1.045uA
7	792.5mV	111.2V	0.933uA	796.8mV	112.5V	0.839uA
8	796.5mV	113.7V	1.134uA	792.6mV	109.6V	0.926uA
9	798.7mV	110.2V	1.157uA	794.8mV	114.7V	1.048uA
10	793.9mV	115.5V	0.870uA	793.9mV	109.8V	0.851uA
11	801.3mV	114.3V	1.034uA	796.2mV	110.0V	1.082uA
12	792.2mV	112.8V	0.999uA	798.7mV	109.4V	1.112uA
13	801.5mV	115.2V	0.952uA	800.1mV	112.1V	1.030uA
14	793.2mV	111.9V	0.882uA	795.2mV	115.4V	0.835uA
15	800.9mV	110.3V	1.071uA	795.0mV	109.4V	0.968uA
16	793.7mV	109.7V	1.061uA	792.9mV	112.0V	0.938uA
17	790.7mV	111.3V	0.926uA	801.4mV	114.1V	0.955uA
18	797.8mV	113.3V	0.849uA	798.1mV	112.1V	0.928uA
19	791.0mV	113.6V	0.998uA	790.6mV	110.5V	1.148uA
20	794.7mV	115.3V	1.117uA	790.8mV	115.2V	0.934uA
21	796.5mV	110.6V	0.924uA	792.6mV	113.6V	0.942uA
22	793.8mV	111.5V	1.163uA	799.5mV	114.3V	1.166uA
23	801.2mV	109.7V	1.072uA	801.1mV	109.8V	0.937uA
24	801.5mV	113.0V	1.146uA	800.8mV	114.1V	1.108uA
25	798.2mV	114.4V	1.107uA	790.4mV	115.3V	1.126uA
26	794.0mV	114.6V	1.010uA	796.4mV	115.3V	1.030uA
27	791.3mV	114.8V	0.991uA	795.1mV	110.5V	0.873uA
28	793.1mV	110.0V	0.851uA	793.2mV	112.2V	0.960uA
29	796.3mV	110.8V	1.155uA	796.8mV	110.2V	0.936uA
30	791.8mV	110.1V	0.911uA	799.1mV	113.2V	0.967uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	793.0mV	111.0V	1.109uA	798.2mV	112.1V	0.968uA
32	799.4mV	115.3V	1.087uA	793.5mV	114.4V	0.934uA
33	791.7mV	115.3V	1.005uA	794.5mV	113.8V	0.881uA
34	797.2mV	109.5V	1.025uA	792.1mV	111.7V	0.840uA
35	795.4mV	111.3V	0.847uA	796.7mV	113.6V	1.099uA
36	792.2mV	110.9V	1.114uA	793.2mV	114.8V	1.094uA
37	795.8mV	114.9V	1.089uA	790.6mV	109.9V	0.905uA
38	792.8mV	114.2V	0.853uA	800.3mV	110.0V	1.164uA
39	800.9mV	111.8V	0.957uA	794.1mV	111.8V	0.856uA
40	790.6mV	112.9V	1.043uA	792.0mV	115.0V	1.137uA
41	796.1mV	114.0V	1.084uA	797.8mV	112.2V	1.165uA
42	794.0mV	112.7V	1.104uA	793.1mV	113.3V	1.150uA
43	797.2mV	112.1V	0.864uA	792.3mV	115.2V	1.108uA
44	797.7mV	111.9V	0.837uA	798.2mV	114.1V	1.100uA
45	796.8mV	110.3V	0.839uA	793.5mV	113.7V	0.852uA
46	790.9mV	109.6V	1.085uA	793.4mV	112.4V	0.915uA
47	798.3mV	113.5V	1.043uA	794.5mV	114.9V	0.977uA
48	791.7mV	112.8V	0.861uA	794.5mV	110.9V	0.829uA
49	794.6mV	110.7V	0.862uA	795.0mV	115.3V	1.004uA
50	796.6mV	112.1V	1.112uA	799.8mV	115.2V	1.023uA
51	794.1mV	114.2V	0.982uA	792.6mV	115.6V	1.005uA
52	794.7mV	115.0V	0.867uA	796.4mV	113.9V	0.973uA
53	793.9mV	114.7V	1.112uA	792.7mV	114.1V	0.945uA
54	796.1mV	110.4V	0.918uA	801.0mV	113.4V	1.037uA
55	792.9mV	114.2V	0.965uA	795.7mV	113.9V	0.872uA
56	792.4mV	112.9V	1.095uA	798.9mV	110.2V	1.032uA
57	792.9mV	111.6V	1.041uA	798.1mV	111.2V	1.151uA
58	799.6mV	110.0V	0.975uA	795.3mV	112.5V	1.081uA
59	799.3mV	115.4V	1.105uA	797.4mV	114.6V	0.977uA
60	793.1mV	111.9V	0.944uA	796.1mV	113.6V	1.153uA



# SeCoS Corporation

## Pressure Cooker Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 121°C, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2014.05.05 ~ 2014.05.11

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	797.6mV	114.6V	0.917uA	800.6mV	113.5V	1.049uA
62	793.2mV	115.5V	1.169uA	798.3mV	110.9V	1.119uA
63	797.5mV	115.2V	0.992uA	800.0mV	111.2V	0.883uA
64	800.1mV	113.6V	0.854uA	797.5mV	112.4V	1.161uA
65	801.0mV	110.0V	1.035uA	791.9mV	111.7V	1.031uA
66	795.2mV	112.8V	1.117uA	795.4mV	113.1V	1.111uA
67	800.4mV	114.1V	0.952uA	800.4mV	115.5V	0.997uA
68	800.9mV	114.0V	0.946uA	800.8mV	111.7V	0.914uA
69	795.1mV	109.9V	1.151uA	801.3mV	115.6V	0.943uA
70	792.4mV	114.9V	0.831uA	793.8mV	113.8V	0.907uA
71	793.3mV	109.8V	1.072uA	791.3mV	114.1V	1.084uA
72	792.8mV	111.1V	0.892uA	796.6mV	115.0V	0.930uA
73	798.0mV	109.8V	0.938uA	791.0mV	113.3V	0.902uA
74	795.7mV	112.8V	1.044uA	794.0mV	114.9V	0.844uA
75	794.1mV	111.0V	0.834uA	799.1mV	112.2V	0.900uA
76	792.6mV	110.4V	0.921uA	797.8mV	109.5V	1.030uA
77	790.9mV	113.6V	0.927uA	801.5mV	109.5V	1.054uA

Made By: Leo Hsia

Approval: Peter Yang



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	792.0mV	111.8V	1.082uA	794.3mV	112.5V	1.158uA
2	800.9mV	111.9V	1.077uA	800.9mV	112.1V	1.026uA
3	795.6mV	110.6V	0.964uA	791.2mV	110.9V	0.999uA
4	800.1mV	110.1V	1.076uA	800.4mV	109.6V	1.062uA
5	792.9mV	114.0V	1.043uA	792.8mV	110.9V	0.978uA
6	800.1mV	110.2V	0.961uA	798.4mV	114.9V	0.876uA
7	800.6mV	113.6V	0.872uA	793.4mV	113.3V	0.933uA
8	800.2mV	114.9V	1.139uA	798.8mV	114.2V	0.942uA
9	797.7mV	110.8V	0.876uA	793.1mV	113.1V	0.950uA
10	796.8mV	112.8V	1.162uA	790.4mV	113.8V	0.945uA
11	793.5mV	115.3V	1.150uA	798.6mV	114.1V	0.871uA
12	796.3mV	111.1V	0.954uA	794.6mV	112.2V	0.930uA
13	795.5mV	111.2V	0.969uA	797.1mV	109.7V	0.899uA
14	799.9mV	110.9V	0.873uA	797.3mV	110.8V	0.847uA
15	790.4mV	109.8V	0.844uA	800.8mV	111.9V	1.094uA
16	791.2mV	110.1V	0.887uA	796.5mV	112.1V	1.032uA
17	799.2mV	111.4V	1.111uA	796.1mV	112.0V	1.011uA
18	796.2mV	114.9V	1.070uA	796.6mV	110.5V	0.871uA
19	793.0mV	111.1V	1.160uA	801.4mV	109.7V	1.052uA
20	791.3mV	112.2V	1.013uA	796.9mV	110.0V	1.091uA
21	794.5mV	112.4V	0.843uA	797.1mV	112.3V	1.146uA
22	791.7mV	113.2V	0.916uA	791.6mV	115.0V	1.096uA
23	793.2mV	111.9V	1.115uA	800.9mV	113.5V	1.015uA
24	791.3mV	114.8V	1.076uA	796.4mV	112.1V	1.004uA
25	800.8mV	112.3V	1.150uA	795.0mV	112.4V	1.010uA
26	791.7mV	114.9V	1.169uA	795.7mV	112.3V	0.858uA
27	794.8mV	113.6V	0.890uA	796.3mV	110.2V	0.868uA
28	799.0mV	115.0V	1.149uA	795.2mV	111.7V	0.874uA
29	791.1mV	115.3V	0.958uA	793.1mV	110.0V	0.927uA
30	796.7mV	113.9V	0.890uA	794.1mV	109.8V	0.877uA





# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	801.0mV	112.3V	0.976uA	796.3mV	110.5V	0.860uA
32	797.6mV	112.5V	0.831uA	795.7mV	114.3V	0.983uA
33	797.7mV	110.3V	0.954uA	794.0mV	113.0V	1.015uA
34	801.3mV	113.5V	0.953uA	799.9mV	114.7V	0.853uA
35	799.3mV	113.1V	0.895uA	791.1mV	114.2V	0.848uA
36	800.4mV	111.0V	0.896uA	797.6mV	115.1V	0.871uA
37	794.2mV	114.1V	0.907uA	798.6mV	109.7V	0.994uA
38	796.8mV	110.7V	0.940uA	796.4mV	110.0V	1.083uA
39	792.1mV	109.7V	0.932uA	793.4mV	113.4V	0.909uA
40	798.4mV	115.1V	0.973uA	798.1mV	112.3V	1.055uA
41	796.1mV	112.4V	0.955uA	791.7mV	110.1V	1.117uA
42	801.1mV	110.2V	0.845uA	792.5mV	114.1V	1.156uA
43	797.7mV	113.1V	1.082uA	795.2mV	115.1V	1.053uA
44	792.1mV	110.8V	0.961uA	795.1mV	115.6V	1.108uA
45	797.7mV	111.6V	0.972uA	797.5mV	115.1V	1.079uA
46	793.3mV	112.2V	1.068uA	795.1mV	114.6V	1.077uA
47	800.0mV	112.2V	0.930uA	792.5mV	114.8V	0.970uA
48	798.5mV	110.4V	0.988uA	791.5mV	115.1V	0.848uA
49	790.5mV	114.6V	0.999uA	794.0mV	115.7V	0.914uA
50	795.0mV	115.3V	1.027uA	793.7mV	109.7V	1.170uA
51	799.0mV	113.8V	1.143uA	794.1mV	112.9V	1.029uA
52	797.1mV	111.6V	0.992uA	800.9mV	115.0V	1.104uA
53	794.9mV	112.5V	0.970uA	798.6mV	115.5V	1.074uA
54	796.4mV	112.7V	1.106uA	795.5mV	113.0V	0.835uA
55	790.9mV	113.7V	1.103uA	792.6mV	113.1V	0.895uA
56	795.0mV	115.6V	0.966uA	797.6mV	110.0V	1.098uA
57	790.6mV	113.2V	0.896uA	795.8mV	111.7V	0.939uA
58	791.8mV	113.6V	0.995uA	796.9mV	110.1V	0.946uA
59	800.4mV	115.3V	1.150uA	801.2mV	112.4V	0.895uA
60	793.9mV	112.1V	0.911uA	796.9mV	113.8V	1.052uA



# SeCoS Corporation

## Temperature Cycle Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: -55°C/30min, 150°C/30min, for1000 Cycle

Test Date: 2014.05.05 ~ 2014.06.25

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	792.8mV	115.2V	1.134uA	797.4mV	111.2V	0.959uA
62	796.2mV	114.5V	0.932uA	798.6mV	111.6V	0.947uA
63	792.1mV	112.1V	0.992uA	794.3mV	114.6V	0.905uA
64	794.9mV	110.8V	0.961uA	794.6mV	111.6V	0.959uA
65	801.1mV	115.5V	1.135uA	798.7mV	109.9V	1.045uA
66	797.4mV	115.6V	0.979uA	793.7mV	112.3V	1.139uA
67	792.3mV	113.3V	0.866uA	792.7mV	113.5V	1.151uA
68	795.5mV	111.6V	1.142uA	796.5mV	113.9V	1.086uA
69	799.0mV	115.0V	0.857uA	798.7mV	113.9V	1.118uA
70	797.6mV	110.5V	0.963uA	796.1mV	112.4V	0.970uA
71	798.5mV	113.0V	0.945uA	801.0mV	110.7V	1.130uA
72	798.7mV	109.7V	0.831uA	792.6mV	110.1V	0.986uA
73	795.9mV	111.3V	1.141uA	795.9mV	113.5V	1.014uA
74	795.9mV	112.7V	1.067uA	799.5mV	115.7V	0.848uA
75	796.5mV	114.3V	1.048uA	792.3mV	111.6V	1.001uA
76	795.2mV	109.8V	0.953uA	794.3mV	115.4V	1.028uA
77	796.2mV	110.4V	1.058uA	800.4mV	110.0V	1.027uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temperature High Humidity Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	801.1mV	114.7V	1.144uA	795.5mV	111.9V	0.858uA
2	801.1mV	113.2V	1.147uA	795.8mV	115.5V	0.904uA
3	791.3mV	115.6V	1.168uA	794.8mV	112.9V	1.121uA
4	790.6mV	111.8V	1.115uA	797.6mV	112.1V	0.911uA
5	793.7mV	114.4V	1.115uA	797.0mV	110.7V	0.884uA
6	792.3mV	113.6V	0.891uA	794.1mV	115.6V	1.129uA
7	799.1mV	111.9V	0.850uA	799.6mV	112.4V	1.152uA
8	791.4mV	115.1V	1.130uA	801.2mV	110.0V	1.113uA
9	799.4mV	111.1V	1.014uA	792.9mV	115.2V	0.943uA
10	796.3mV	112.5V	1.020uA	796.5mV	115.1V	1.061uA
11	800.8mV	115.3V	1.024uA	795.7mV	113.7V	1.099uA
12	793.2mV	109.5V	0.990uA	791.7mV	111.9V	0.955uA
13	795.9mV	115.2V	0.891uA	791.2mV	109.6V	1.151uA
14	799.5mV	113.6V	1.168uA	790.9mV	114.6V	1.167uA
15	798.3mV	113.8V	0.884uA	791.4mV	109.7V	0.944uA
16	794.9mV	110.5V	1.076uA	801.3mV	112.1V	1.112uA
17	790.9mV	111.1V	0.992uA	797.1mV	111.4V	1.162uA
18	794.9mV	114.4V	0.861uA	796.8mV	114.9V	0.853uA
19	801.0mV	113.2V	0.876uA	792.6mV	114.5V	1.037uA
20	801.4mV	111.8V	1.146uA	791.6mV	110.3V	1.070uA
21	794.1mV	113.8V	1.150uA	794.7mV	112.0V	0.957uA
22	792.3mV	112.9V	1.131uA	791.8mV	111.6V	0.900uA
23	797.1mV	110.7V	0.889uA	801.2mV	114.4V	0.997uA
24	790.5mV	113.4V	1.060uA	795.2mV	114.1V	1.169uA
25	798.9mV	112.2V	1.157uA	793.8mV	111.6V	0.960uA
26	796.2mV	114.9V	0.940uA	799.6mV	110.4V	0.894uA
27	791.2mV	114.5V	0.939uA	798.0mV	110.1V	1.105uA
28	798.0mV	112.7V	1.118uA	798.0mV	112.8V	1.101uA
29	799.7mV	113.8V	1.163uA	794.0mV	113.9V	1.125uA
30	796.3mV	112.6V	0.913uA	796.4mV	110.3V	1.168uA



## High Temperature High Humidity Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	794.6mV	112.3V	1.112uA	798.2mV	115.6V	1.106uA
32	793.0mV	115.1V	1.166uA	791.3mV	111.6V	1.028uA
33	799.0mV	110.8V	1.144uA	793.6mV	113.6V	0.945uA
34	791.4mV	112.6V	0.860uA	800.6mV	111.4V	1.117uA
35	794.4mV	112.2V	1.050uA	793.7mV	109.7V	0.891uA
36	795.6mV	114.2V	0.897uA	795.5mV	115.1V	1.020uA
37	796.4mV	112.8V	0.838uA	792.7mV	113.0V	1.140uA
38	801.1mV	114.1V	0.878uA	799.9mV	111.3V	0.854uA
39	790.5mV	112.6V	0.967uA	791.0mV	112.0V	1.155uA
40	792.3mV	113.4V	0.870uA	801.1mV	110.2V	1.104uA
41	793.9mV	109.5V	0.843uA	792.2mV	112.1V	0.962uA
42	790.8mV	111.4V	0.959uA	800.3mV	111.6V	0.984uA
43	801.3mV	109.6V	0.999uA	791.6mV	113.4V	1.029uA
44	792.8mV	115.1V	0.846uA	799.4mV	109.9V	1.002uA
45	797.1mV	112.6V	1.064uA	792.4mV	113.4V	0.996uA
46	800.1mV	110.1V	0.830uA	791.5mV	110.7V	1.156uA
47	794.1mV	110.9V	0.999uA	796.2mV	110.9V	1.131uA
48	800.5mV	110.0V	1.137uA	795.8mV	112.4V	0.949uA
49	801.2mV	114.2V	0.838uA	793.1mV	113.7V	0.857uA
50	792.4mV	113.0V	1.137uA	790.5mV	111.3V	1.032uA
51	794.0mV	110.8V	1.075uA	800.6mV	114.9V	1.118uA
52	798.8mV	112.2V	1.150uA	793.1mV	114.2V	0.942uA
53	798.5mV	109.5V	0.997uA	793.5mV	112.4V	1.004uA
54	791.3mV	111.3V	1.137uA	797.7mV	112.4V	1.005uA
55	798.1mV	109.4V	1.010uA	795.7mV	114.9V	0.980uA
56	794.2mV	111.3V	1.002uA	798.7mV	114.2V	0.891uA
57	793.3mV	115.6V	0.983uA	790.8mV	110.7V	0.945uA
58	793.8mV	113.2V	1.068uA	797.2mV	109.9V	1.111uA
59	797.9mV	109.4V	0.948uA	792.8mV	115.4V	1.103uA
60	799.2mV	113.8V	0.828uA	791.2mV	113.2V	0.908uA



## High Temperature High Humidity Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	790.6mV	113.1V	1.149uA	800.2mV	113.8V	0.963uA
62	798.8mV	110.4V	1.151uA	796.4mV	112.1V	0.851uA
63	792.4mV	114.9V	1.124uA	799.0mV	112.9V	1.148uA
64	799.4mV	109.5V	0.868uA	797.4mV	109.6V	1.081uA
65	798.9mV	113.9V	0.963uA	795.6mV	113.4V	0.842uA
66	797.0mV	109.9V	1.099uA	793.6mV	113.4V	1.033uA
67	791.7mV	115.5V	1.042uA	797.0mV	109.7V	0.903uA
68	798.3mV	112.7V	0.938uA	796.5mV	109.5V	0.929uA
69	793.9mV	112.2V	1.170uA	791.5mV	111.5V	1.048uA
70	791.7mV	113.7V	1.050uA	794.4mV	112.3V	0.944uA
71	798.5mV	113.5V	0.898uA	794.8mV	111.7V	0.874uA
72	795.4mV	110.6V	0.857uA	798.9mV	110.4V	0.859uA
73	798.4mV	113.6V	1.078uA	798.2mV	109.6V	0.925uA
74	794.6mV	115.2V	0.956uA	799.5mV	110.6V	1.064uA
75	792.2mV	114.7V	1.168uA	798.7mV	112.1V	0.902uA
76	797.5mV	113.6V	1.100uA	794.9mV	115.1V	1.166uA
77	796.1mV	112.3V	0.875uA	795.4mV	115.4V	0.927uA

Made By: Leo Hsia

Approval: Peter Yang



## High Temper High Humidity Reverse Bies Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	796.6mV	114.8V	0.866uA	793.5mV	115.0V	0.959uA
2	799.7mV	110.6V	1.034uA	793.7mV	111.1V	0.972uA
3	793.9mV	112.8V	0.942uA	799.5mV	110.8V	1.069uA
4	800.6mV	114.9V	1.112uA	792.6mV	111.9V	0.892uA
5	801.1mV	110.4V	1.113uA	797.1mV	109.6V	0.872uA
6	798.3mV	110.8V	1.020uA	791.6mV	112.1V	0.998uA
7	796.7mV	111.3V	1.063uA	790.5mV	113.8V	1.016uA
8	792.3mV	110.7V	0.865uA	800.2mV	112.7V	0.839uA
9	801.0mV	112.2V	1.094uA	792.3mV	109.4V	0.834uA
10	796.9mV	114.7V	0.969uA	798.1mV	113.7V	1.033uA
11	799.5mV	113.1V	0.982uA	793.7mV	109.4V	1.120uA
12	793.2mV	112.5V	0.893uA	797.9mV	112.8V	1.094uA
13	800.7mV	111.1V	1.039uA	790.6mV	109.8V	1.013uA
14	795.6mV	110.1V	0.958uA	797.1mV	112.8V	0.887uA
15	794.2mV	110.4V	0.972uA	797.4mV	115.6V	0.967uA
16	799.6mV	115.7V	0.865uA	790.8mV	111.1V	0.903uA
17	797.7mV	113.5V	1.155uA	796.2mV	112.8V	1.114uA
18	795.6mV	109.5V	1.023uA	800.9mV	113.7V	1.056uA
19	793.2mV	112.5V	1.002uA	790.7mV	109.9V	1.036uA
20	800.0mV	115.4V	1.168uA	797.0mV	113.5V	1.157uA
21	790.8mV	114.9V	0.884uA	798.0mV	113.5V	0.883uA
22	795.8mV	113.4V	1.008uA	793.0mV	114.3V	0.922uA
23	793.6mV	111.2V	1.062uA	793.3mV	112.8V	0.858uA
24	794.3mV	110.1V	1.028uA	793.9mV	115.5V	1.084uA
25	796.8mV	112.7V	0.840uA	800.2mV	110.3V	1.096uA
26	792.0mV	115.1V	1.048uA	793.6mV	112.5V	1.072uA
27	793.2mV	111.0V	1.112uA	793.6mV	114.2V	0.983uA
28	792.9mV	109.8V	1.029uA	793.0mV	112.5V	0.864uA
29	799.8mV	113.1V	1.082uA	795.1mV	110.8V	1.075uA
30	793.6mV	110.3V	1.132uA	800.0mV	111.9V	0.989uA



## High Temper High Humidity Reverse Bies Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
31	801.4mV	115.5V	1.108uA	792.9mV	111.7V	1.024uA
32	798.3mV	111.4V	0.964uA	800.4mV	115.1V	0.958uA
33	800.5mV	109.8V	0.882uA	796.9mV	110.5V	1.080uA
34	792.4mV	110.6V	0.938uA	794.1mV	110.8V	0.930uA
35	790.8mV	110.7V	1.022uA	793.7mV	109.5V	0.994uA
36	798.8mV	109.7V	1.106uA	795.5mV	112.1V	1.067uA
37	793.3mV	113.3V	0.944uA	798.8mV	113.6V	1.103uA
38	794.0mV	111.3V	1.086uA	790.4mV	115.4V	0.874uA
39	793.9mV	112.8V	1.092uA	799.9mV	109.6V	0.907uA
40	801.2mV	113.8V	0.872uA	791.9mV	113.5V	0.998uA
41	800.1mV	110.3V	1.065uA	794.6mV	111.7V	0.902uA
42	793.1mV	111.1V	0.988uA	800.9mV	110.8V	0.889uA
43	797.3mV	113.9V	0.890uA	791.6mV	115.4V	0.965uA
44	792.1mV	112.6V	0.954uA	792.9mV	114.8V	0.828uA
45	792.4mV	112.9V	1.142uA	792.3mV	112.3V	1.065uA
46	790.9mV	111.0V	1.143uA	791.8mV	115.4V	1.056uA
47	794.4mV	111.0V	1.004uA	799.1mV	111.9V	0.959uA
48	796.0mV	115.4V	1.087uA	794.8mV	111.8V	0.888uA
49	791.8mV	110.8V	0.835uA	799.9mV	112.9V	1.080uA
50	798.4mV	112.8V	0.827uA	798.5mV	113.7V	0.897uA
51	795.9mV	112.6V	0.901uA	799.2mV	112.3V	1.113uA
52	794.1mV	114.4V	1.073uA	801.2mV	111.9V	0.897uA
53	796.5mV	111.9V	1.132uA	795.7mV	110.3V	1.076uA
54	795.4mV	111.4V	0.979uA	794.0mV	111.8V	1.136uA
55	791.6mV	110.2V	0.867uA	799.5mV	113.2V	0.913uA
56	795.3mV	111.6V	1.134uA	795.2mV	112.0V	0.873uA
57	790.4mV	115.5V	0.893uA	801.4mV	114.6V	0.953uA
58	799.4mV	110.2V	0.950uA	798.7mV	112.0V	0.990uA
59	792.0mV	114.8V	0.949uA	794.8mV	115.0V	1.062uA
60	796.7mV	112.9V	1.102uA	797.0mV	115.0V	1.154uA



## High Temper High Humidity Reverse Bies Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 85±2°C, 85±5%RH, 1000Hrs

Test Date: 2014.05.11 ~ 2014.06.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
61	791.5mV	113.9V	1.169uA	794.1mV	115.4V	0.926uA
62	799.8mV	115.2V	0.951uA	791.8mV	111.7V	0.960uA
63	796.8mV	110.2V	0.899uA	799.0mV	114.1V	1.141uA
64	791.8mV	112.9V	1.031uA	795.2mV	112.4V	0.932uA
65	790.8mV	111.5V	0.986uA	794.4mV	110.0V	1.135uA
66	796.3mV	111.9V	1.060uA	795.4mV	110.9V	0.910uA
67	795.1mV	109.9V	1.067uA	797.3mV	110.2V	0.951uA
68	790.3mV	110.4V	0.945uA	794.7mV	115.2V	1.110uA
69	793.4mV	115.1V	0.984uA	791.2mV	111.7V	0.855uA
70	799.9mV	114.2V	0.926uA	793.5mV	112.7V	0.971uA
71	799.2mV	111.6V	0.908uA	801.5mV	115.4V	1.131uA
72	800.4mV	114.8V	1.169uA	797.1mV	111.1V	1.045uA
73	795.7mV	112.7V	1.016uA	799.6mV	113.9V	0.883uA
74	795.9mV	110.3V	1.135uA	790.8mV	114.5V	0.853uA
75	791.2mV	109.8V	0.860uA	794.7mV	111.5V	0.906uA
76	796.8mV	111.0V	0.868uA	799.8mV	114.6V	1.041uA
77	798.5mV	115.7V	1.167uA	794.2mV	109.5V	1.112uA

Made By: Leo Hsia

Approval: Peter Yang





# SeCoS Corporation

## Solderability Test Data

Report No : T140630-031

Part No : SCS1100P

Test Equipment: JUNO Test System DTS-1000

Test Condition : VF<830mV@IF=1A, VB>100V@I=1mA, IR<50uA@VR=100V

Test Condition: 245°C ± 5°C, 5Sec

Test Date: 2014.06.28 ~ 2014.06.28

Test Standard : JESD22 STANDER Method-B102

Operator: Leo Hsia

Test Result: PASS

No	Before			After		
	VF (mV)	VB (V)	IR (uA)	VF (mV)	VB (V)	IR (uA)
1	793.3mV	111.8V	1.059uA	799.9mV	114.2V	0.855uA
2	799.8mV	109.8V	0.861uA	793.0mV	115.7V	1.033uA
3	793.3mV	110.4V	1.005uA	798.3mV	113.9V	1.055uA
4	797.2mV	111.3V	1.007uA	795.4mV	115.5V	1.035uA
5	797.6mV	110.2V	1.095uA	796.8mV	112.5V	0.954uA
6	798.1mV	113.3V	1.031uA	801.1mV	112.5V	1.017uA
7	792.4mV	115.5V	1.033uA	793.8mV	113.0V	0.852uA
8	797.6mV	111.6V	0.981uA	794.9mV	110.0V	1.136uA
9	799.5mV	114.1V	0.987uA	800.8mV	114.1V	0.826uA
10	796.0mV	114.9V	1.057uA	790.5mV	113.9V	0.992uA

Made By: Leo Hsia

Approval: Peter Yang